

A Cross-Bridge Kelvin Resistor Model for the Extraction of Specific Contact Resistivity

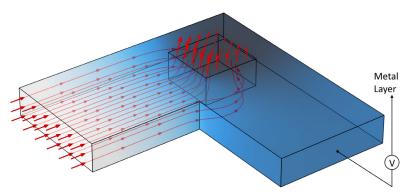
This benchmark example builds two models of a cross-bridge Kelvin resistor used for extracting the specific contact resistivity. The first model simulates the system in 3D, using the contact resistance feature in the Semiconductor interface. The other model is a 2D approximation of the system developed in the reference paper, implemented using a boundary PDE math interface. The computed Kelvin contact resistance as a function of the contact window size and the diffusion tap width correlates well between the two models, and agrees well with the result shown in the reference paper.

Introduction

Cross-bridge Kelvin resistor structures are commonly used to characterize the contact resistance of metal–semiconductor contacts. This tutorial examines a specific series of test structures described in the reference paper (Ref. 1), using a 3D semiconductor model and a 2D approximate model (the latter being developed in Ref. 2). The simulated Kelvin contact resistance as a function of the contact window size and the diffusion tap width will be compared between the two models and will be compared with the experimental and simulated results from Ref. 1.

Model Definition

The test structure is shown in the sketch below.

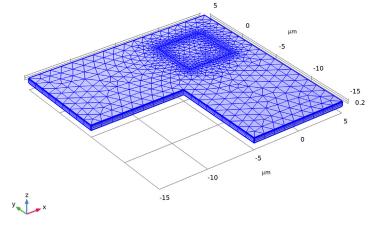


A 5000 Å thick n^+ doped polysilicon layer is patterned to an "L" shape as shown in the sketch above. Current is injected into the left arm of the "L" and exits through a square contact window to a metal layer above, as indicated by the red arrows (the metal layer is not shown in the sketch). A voltmeter measures the voltage drop between the right arm of the "L" and the metal layer. The *Kelvin contact resistance* R_c is defined as this voltage drop divided by the total current flowing through the contact window (SI unit: Ω).

The metal–semiconductor contact is characterized by the *specific contact resistivity* ρ_c (voltage drop divided by the current density within an infinitesimal contact area, SI unit: $\Omega \cdot m^2$). Because the distribution of the current density through the contact window is very nonuniform (current crowding effect), it is not straightforward to calculate the *specific contact resistivity* ρ_c from the *Kelvin contact resistance* R_c . Therefore, it is necessary to use numerical simulation to extract the *specific contact resistivity* ρ_c from experimental data.

In the experiment reported in Ref. 1, two series of test structures with various dimensions are used to verify the simulation approach. In the first series, the contact window size l is varied from 5 to 65 μ m, while the diffusion tap width w is maintained 5 μ m larger than l. In the second series, the diffusion tap width w is varied from 7.5 to 60 μ m, while the contact window size l is kept constant at 5 μ m. A 2D approximate model of the system (detailed in Ref. 2) is used to generate a family of R_c –l and R_c –w curves with various values of ρ_c . These curves are then compared with experimental data to obtain the optimal value of ρ_c for the contact (Fig. 2 and 3 in Ref. 1).

In this tutorial model, the geometry is parameterized, and **Parametric Sweep** is used in two separate studies for the two series of test structures discussed above. To save computation time and file size, only the optimal value of ρ_c is computed in this example. However, different values of ρ_c can easily be added by using **Auxiliary sweep**. The test structure is modeled both in 3D using the **Semiconductor** interface with its built-in Contact resistance functionality, and in 2D using the **General Form Boundary PDE** interface to implement the approximate model described in Ref. 2. The figure below shows the mesh.



See the comments in the section Modeling Instructions for more detailed discussions on the model construction, solution processes, and result visualization.

Figure 1 shows the simulated R_c —area curve for the first series, to be compared with Fig. 2 in Ref. 1. The two models both agree well with the reference paper.

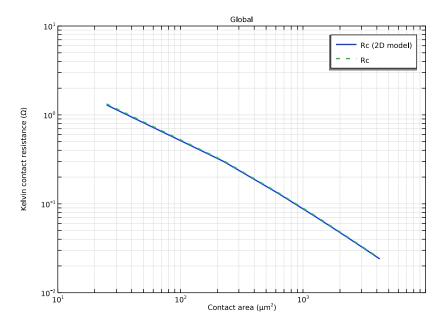


Figure 1: R_c -area curve for the first test structure series.

Figure 2 plots the R_c –w curve for the second series, to be compared with Fig. 3 in Ref. 1. The two models both agree well with the reference paper.

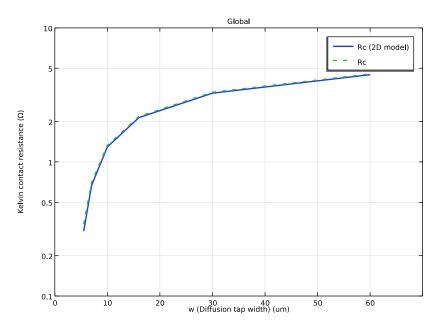


Figure 2: R_c -w curve for the second test structure series.

References

- 1. W.M. Loh, S.E. Swirhun, E. Crabbe, K. Saraswat, and R. M. Swanson, "An accurate method to extract specific contact resistivity using cross-bridge Kelvin resistors," *IEEE Electron Device Letters*, vol. 6, no. 9, pp. 441–443, 1985, doi: 10.1109/EDL.1985.26185.
- 2. W. M. Loh, S.E. Swirhun, T.A. Schreyer, R.M. Swanson, and K.C. Saraswat, "Modeling and measurement of contact resistances," *IEEE Transactions on Electron Devices*, vol. 34, no. 3, pp. 512–524, 1987, doi: 10.1109/T-ED.1987.22957.

Application Library path: Semiconductor_Module/Device_Building_Blocks/cross_bridge_kelvin_resistor_contact_resistivity

From the File menu, choose New.

NEW

In the New window, click Model Wizard.

MODEL WIZARD

- I In the **Model Wizard** window, Use 3D geometry to model the cross-bridge Kelvin resistor.
- 2 click **1 3D**.

Add the Semiconductor physics (to be solved in 3D) and a math interface for the 2D model (to be solved on the top surface of the 3D geometry). For the latter, set the dependent variable to V2D with the unit of voltage and also set the unit of the source term accordingly.

- 3 In the Select Physics tree, select Semiconductor>Semiconductor (semi).
- 4 Click Add.
- 5 In the Select Physics tree, select Mathematics>PDE Interfaces>Lower Dimensions> General Form Boundary PDE (gb).
- 6 Click Add.
- 7 In the Field name (1) text field, type V2D.
- 8 In the Dependent variables (1) table, enter the following settings:

V2D

- 9 Click Define Dependent Variable Unit.
- 10 In the Dependent variable quantity table, enter the following settings:

Dependent variable quantity	Unit
Custom unit	V

II Click Define Source Term Unit.

12 In the Source term quantity table, enter the following settings:

Source term quantity	Unit
Custom unit	V*m^-2

Add a Stationary study.

13 Click 🔵 Study.

14 In the Select Study tree, select General Studies>Stationary.

15 Click **Done**.

GEOMETRY I

Set the length unit to µm for convenience.

- I In the Model Builder window, under Component I (compl) click Geometry I.
- 2 In the Settings window for Geometry, locate the Units section.
- 3 From the Length unit list, choose μm .

Add model parameters.

GLOBAL DEFINITIONS

Parameters I

- I In the Model Builder window, under Global Definitions click Parameters I.
- 2 In the Settings window for Parameters, locate the Parameters section.
- **3** In the table, enter the following settings:

Name	Expression	Value	Description
1	5[um]	5E-6 m	Contact window size
W	1+5[um]	1E-5 m	Diffusion tap width
lb	W	1E-5 m	Length of bridge
d	5000[angstrom]	5E-7 m	Thickness of Si
Rs	11.0[ohm]	ΠΩ	Sheet resistance
mun0	1450[cm^2/(V*s)]	0.145 m ² /(V·s)	Electron mobility
Nd0	1/(d*e_const*mun0* Rs)	7.8263E24 I/m³	Doping concentration from Rs
rho_c	4.5e-8[ohm*cm^2]	4.5E-12 Ω·m²	Specific contact resistivity
lt	sqrt(rho_c/Rs)	6.396E-7 m	Transfer length
V0	100[uV]	IE-4 V	Applied voltage

Create the geometry for the 5000 angstrom thick n+ silicon layer, using a work plane to first draw the 2D shape of the bridge and then extrude in the thickness direction to 3D. The contacts will be modeled as boundary conditions with the metal layer assumed to be a perfect conductor.

GEOMETRY I

Work Plane I (wbl)

In the Geometry toolbar, click Work Plane.

Work Plane I (wp I)>Plane Geometry

In the Model Builder window, click Plane Geometry.

Square I - Contact window

- I In the Work Plane toolbar, click Square.
- 2 In the Settings window for Square, type Square 1 Contact window in the Label text field.
- 3 Locate the Size section. In the Side length text field, type 1.
- 4 Locate the Position section. From the Base list, choose Center.

Polygon I - Bridge

- I In the Work Plane toolbar, click / Polygon.
- ${f 2}$ In the Settings window for Polygon, type Polygon 1 Bridge in the Label text field.
- **3** Locate the **Coordinates** section. In the table, enter the following settings:

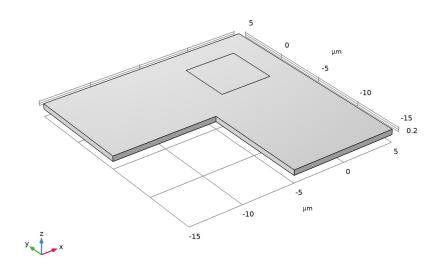
xw (µm)	yw (µm)	
-w/2-1b	-w/2	
-w/2-1b	w/2	
w/2	w/2	
w/2	-w/2-1b	
-w/2	-w/2-1b	
-w/2	-w/2	
-w/2-1b	-w/2	

Extrude I (extI)

- I In the Model Builder window, right-click Geometry I and choose Extrude.
- 2 In the Settings window for Extrude, locate the Distances section.
- **3** In the table, enter the following settings:

Distances (µm)	
d	

4 Click Build All Objects.



Add silicon material properties from the library. Use the electron mobility parameter mun0 defined earlier.

ADD MATERIAL

- I In the Home toolbar, click **Add Material** to open the Add Material window.
- 2 Go to the Add Material window.
- 3 In the tree, select Semiconductors>Si Silicon.
- 4 Click Add to Component in the window toolbar.
- 5 In the Home toolbar, click 44 Add Material to close the Add Material window.

MATERIALS

Si - Silicon (mat I)

- I In the Settings window for Material, locate the Material Contents section.
- **2** In the table, enter the following settings:

Property	Variable	Value	Unit	Property group
Electron mobility	mun	mun0	m²/(V·s)	Semiconductor material

Set up physics conditions. Since the silicon is heavily n-doped, we only need to solve the majority carriers (electrons). Specify the uniform doping and three metal contacts (for the input current, bridge voltmeter, and contact window to the grounded upper metal layer).

SEMICONDUCTOR (SEMI)

- I In the Model Builder window, under Component I (compl) click Semiconductor (semi).
- 2 In the Settings window for Semiconductor, locate the Model Properties section.
- 3 From the Solution list, choose Majority carriers only.

Analytic Doping Model I

- I In the Physics toolbar, click **Domains** and choose Analytic Doping Model.
- 2 In the Settings window for Analytic Doping Model, locate the Domain Selection section.
- 3 From the Selection list, choose All domains.
- 4 Locate the Impurity section. From the Impurity type list, choose Donor doping (n-type).
- **5** In the N_{D0} text field, type Nd0.

Metal Contact I - Input current

- I In the Physics toolbar, click **Boundaries** and choose **Metal Contact**.
 - For the input current, it is easier to solve by using a voltage-driven metal contact with a small bias voltage parameter V0 (defined earlier), and then read off the terminal current after solving.
- 2 In the Settings window for Metal Contact, type Metal Contact 1 Input current in the Label text field.
- **3** Select Boundary 1 only.
- **4** Locate the **Terminal** section. In the V_0 text field, type V0.

Metal Contact 2 - Bridge voltmeter

- I In the Physics toolbar, click **Boundaries** and choose **Metal Contact**.
 - For the contact to the bridge voltmeter, assume infinite impedance (zero current). Use the same voltage parameter V0 as an offset to facilitate convergence.
- 2 In the Settings window for Metal Contact, type Metal Contact 2 Bridge voltmeter in the Label text field.
- **3** Select Boundary 7 only.
- 4 Locate the Terminal section. From the Terminal type list, choose Current.
- **5** In the V_{init} text field, type V0.

Metal Contact 3 - Contact window

- In the Physics toolbar, click Boundaries and choose Metal Contact.

 Use the built-in contact resistance option for the contact resistance at the contact window, which is connected to a grounded upper metal layer (zero volt). Define a selection of the contact window boundary for later use.
- 2 In the **Settings** window for **Metal Contact**, type Metal Contact 3 Contact window in the **Label** text field.
- **3** Select Boundary 11 only.
- 4 Locate the Boundary Selection section. Click \(\frac{1}{2}\) Create Selection.
- 5 In the Create Selection dialog box, type Contact window in the Selection name text field.
- 6 Click OK.
- 7 In the Settings window for Metal Contact, locate the Terminal section.
- **8** Select the **Contact resistance** check box.
- **9** In the ρ_c text field, type rho_c.

Next set up the 2D model (Eq. 17 in the reference paper) using the math interface **General Form Boundary PDE**. Select the top surface of the bridge structure. The units of the dependent variable and source term have already been specified earlier.

GENERAL FORM BOUNDARY PDE (GB)

- I In the Model Builder window, under Component I (compl) click General Form Boundary PDE (gb).
- 2 In the Settings window for General Form Boundary PDE, locate the Boundary Selection section.
- 3 Click Clear Selection.
- 4 Select Boundaries 4 and 11 only.

Use the default domain condition for the left-hand side of Eq. 17 in the reference paper. Expand the **Equation** section of the Settings window to see how to adjust the inputs to match the equation in the paper. In this case, remove the minus signs of the flux components and zero out the source term and damping coefficient.

General Form PDE 1 - L.H.S. of Eq. 17 in ref. paper

- I In the Model Builder window, under Component I (compl)>
 General Form Boundary PDE (gb) click General Form PDE I.
- 2 In the Settings window for General Form PDE, type General Form PDE 1 L.H.S. of Eq. 17 in ref. paper in the Label text field.

3 Click to expand the **Equation** section. Locate the **Conservative Flux** section. Specify the Γ vector as

V2DTx	x
V2DTy	у
V2DTz	z

- **4** Locate the **Source Term** section. In the f text field, type **0**.
- **5** Locate the **Damping or Mass Coefficient** section. In the d_a text field, type 0.

Add a source term for the right-hand side of Eq. 17 in the reference paper. Select only the contact window - the source term is zero in other regions (Eq. 19 in the reference paper). The selection can be made easily by using the selection defined earlier, now appears in the **Selection:** drop-down menu.

Source I - R.H.S. of Eq. 17 in ref. paper

- I In the Physics toolbar, click **Boundaries** and choose **Source**.
- 2 In the Settings window for Source, type Source 1 R.H.S. of Eq. 17 in ref. paper in the Label text field.
- 3 Locate the Boundary Selection section. From the Selection list, choose Contact window.
- **4** Locate the **Source Term** section. In the f text field, type V2D/1t^2.

For the input current contact, apply the same bias voltage parameter V0 at the corresponding boundary (also create a selection for later use). To obtain an accurate result for the terminal current, use the weak constraint, which becomes visible in the GUI after turning on **Advanced Physics Options**.

Dirichlet Boundary Condition 1 - Input current

- I In the Physics toolbar, click Edges and choose Dirichlet Boundary Condition.
- 2 In the **Settings** window for **Dirichlet Boundary Condition**, type Dirichlet Boundary Condition 1 Input current in the **Label** text field.
- 3 Select Edge 4 only.
- **4** Locate the **Dirichlet Boundary Condition** section. In the r text field, type V0.
- 5 Locate the Edge Selection section. Click \(\frac{1}{2} \) Create Selection.
- **6** In the **Create Selection** dialog box, type Input current (2D model) in the **Selection name** text field.
- 7 Click OK.
- 8 Click the Show More Options button in the Model Builder toolbar.

- **9** In the **Show More Options** dialog box, in the tree, select the check box for the node **Physics>Advanced Physics Options**.
- IO Click OK.
- II In the Settings window for Dirichlet Boundary Condition, click to expand the Constraint Settings section.
- 12 Select the Weak constraints check box.

Define integration operators and variables to evaluate the terminal currents using the Lagrange multipliers from the weak constraints (using Eq. 21a from the reference paper) for the input current and the voltmeter current, and using Eq. 21b from the reference paper for the contact window current.

DEFINITIONS

Integration I - Input current

- I In the Definitions toolbar, click Nonlocal Couplings and choose Integration.
- 2 In the Settings window for Integration, type Integration 1 Input current in the Label text field.
- 3 Locate the Source Selection section. From the Geometric entity level list, choose Edge.
- 4 From the Selection list, choose Input current (2D model).

Integration 2 - Bridge voltmeter

- I In the Definitions toolbar, click // Nonlocal Couplings and choose Integration.
- 2 In the **Settings** window for **Integration**, type Integration 2 Bridge voltmeter in the **Label** text field.
- 3 Locate the Source Selection section. From the Geometric entity level list, choose Edge.
- 4 Select Edge 13 only.
- 5 Click **\(\)** Create Selection.
- **6** In the **Create Selection** dialog box, type Bridge voltmeter (2D model) in the **Selection name** text field.
- 7 Click OK.

Integration 3 - Contact window

- I In the **Definitions** toolbar, click **Nonlocal Couplings** and choose **Integration**.
- 2 In the Settings window for Integration, type Integration 3 Contact window in the Label text field.

- **3** Locate the **Source Selection** section. From the **Geometric entity level** list, choose **Boundary**.
- 4 From the Selection list, choose Contact window.

Variables 1

- I In the Model Builder window, right-click Definitions and choose Variables.
- 2 In the Settings window for Variables, locate the Variables section.
- **3** In the table, enter the following settings:

Name	Expression	Unit	Description
I2D_1	intop1(V2D_lm[V/m]/Rs)	Α	Input current (2D model)
I2D_2	<pre>intop2(V2D_lm[V/m]/Rs)</pre>	Α	Voltmeter current (2D model)
I2D_3	intop3(V2D/rho_c)	Α	Contact window current (2D model)

For the bridge voltmeter contact, apply an unknown bias voltage V2D_ode at the corresponding boundary (a selection has been defined earlier when defining the integration operator). Then solve for the unknown voltage using a global equation requiring that the voltmeter current I2D 2 is zero (assuming infinite impedance).

GENERAL FORM BOUNDARY PDE (GB)

Dirichlet Boundary Condition 2 - Bridge voltmeter

- I In the Physics toolbar, click Edges and choose Dirichlet Boundary Condition.
- 2 In the Settings window for Dirichlet Boundary Condition, type Dirichlet Boundary Condition 2 Bridge voltmeter in the Label text field.
- 3 Locate the Edge Selection section. From the Selection list, choose Bridge voltmeter (2D model).
- 4 Locate the Dirichlet Boundary Condition section. In the r text field, type V2D_ode.
- **5** Click to expand the **Constraint Settings** section. Select the **Weak constraints** check box.

Global Equations 1 - Bridge voltmeter

- I In the Physics toolbar, click A Global and choose Global Equations.
- 2 In the **Settings** window for **Global Equations**, type **Global Equations** 1 Bridge voltmeter in the **Label** text field.
- 3 Locate the Units section. Click Define Dependent Variable Unit.

4 In the Dependent variable quantity table, enter the following settings:

Dependent variable quantity	Unit
Custom unit	V

- 5 Click Define Source Term Unit.
- **6** In the **Source term quantity** table, enter the following settings:

Source term quantity	Unit
Custom unit	Α

7 Locate the Global Equations section. In the table, enter the following settings:

Name	f(u,ut,utt, t) (A)	Initial value (u_0) (V)	Initial value (u_t0) (V/s)	Description
V2D_ode	I2D_2	0	0	

Create a Swept mesh which is required by the default finite volume discretization. Make sure the mesh is fine enough around the perimeter of the contact window where large gradients exist by parameterizing the mesh sizes with geometric dimensions.

MESH I

Edge I

- I In the Mesh toolbar, click More Generators and choose Edge.
- 2 Select Edges 18, 19, 22, and 25 only.

Distribution I

- I Right-click **Edge I** and choose **Distribution**.
- 2 In the Settings window for Distribution, locate the Distribution section.
- 3 In the Number of elements text field, type 20*1/5[um].

Size

- I In the Model Builder window, under Component I (compl)>Mesh I click Size.
- 2 In the Settings window for Size, locate the Element Size section.
- **3** Click the **Custom** button.
- **4** Locate the **Element Size Parameters** section. In the **Maximum element size** text field, type **1.2**.
- 5 In the Maximum element growth rate text field, type 1.3.

Free Triangular 1

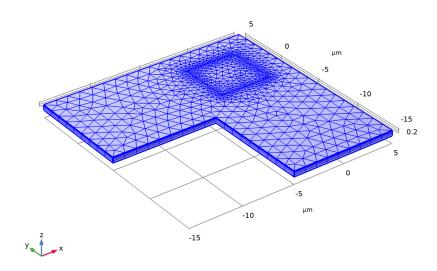
- I In the Mesh toolbar, click A More Generators and choose Free Triangular.
- 2 Select Boundaries 4 and 11 only.

Swept I

In the Mesh toolbar, click & Swept.

Distribution I

- I Right-click Swept I and choose Distribution.
- 2 In the Settings window for Distribution, locate the Distribution section.
- 3 From the Distribution type list, choose Predefined.
- 4 In the Element ratio text field, type 5.
- 5 Click Build All.



Add an outer **Parametric Sweep** to sweep the contact window size l from 5 to 65 um, to be compared with the result shown in Fig. 2 of the reference paper.

STUDY I - RC VS. L

- I In the Model Builder window, click Study I.
- 2 In the Settings window for Study, type Study 1 Rc vs. 1 in the Label text field.

- I In the Study toolbar, click Parametric Sweep.
- 2 In the Settings window for Parametric Sweep, locate the Study Settings section.
- 3 Click + Add.
- **4** In the table, enter the following settings:

Parameter name	Parameter value list	Parameter unit
I (Contact window size)	range(5,10,65)	um

5 In the Study toolbar, click **Compute**.

Evaluate and compare the bridge voltage and the terminal currents from the 3D semiconductor model and 2D simplified model. There is a good correlation between the results from the 2D and 3D models. Within each model, the input current agrees with the contact window current, and the bridge voltmeter current is essentially zero, both as expected.

RESULTS

Evaluation Group I - Rc vs. I

- I In the Results toolbar, click Evaluation Group.
- 2 In the **Settings** window for **Evaluation Group**, type Evaluation Group 1 Rc vs. 1 in the **Label** text field.
- 3 Locate the Data section. From the Dataset list, choose Study I Rc vs. I/ Parametric Solutions I (sol2).

Global Evaluation 1

- I Right-click Evaluation Group I Rc vs. I and choose Global Evaluation.
- ${\bf 2}\ \ {\rm In}\ {\rm the}\ {\bf Settings}\ {\rm window}\ {\rm for}\ {\bf Global}\ {\bf Evaluation},\ {\rm locate}\ {\rm the}\ {\bf Expressions}\ {\rm section}.$
- 3 In the table, enter the following settings:

Expression	Unit	Description		
V2D_ode	V	Bridge voltmeter (2D model)		
semi.VO_2	V	Bridge voltmeter		
I2D_1	Α	Input current (2D model)		
I2D_3	Α	Contact window current (2D model)		
semi.IO_1	Α	Input current		
semi.IO_3	Α	Contact window current		

Expression	Unit	Description
I2D_2	Α	Voltmeter current (2D model)
semi.IO_2	Α	Voltmeter current

4 In the Evaluation Group I - Rc vs. I toolbar, click **= Evaluate**.

Create a plot of the simulated Kelvin contact resistance R_c as a function of the contact window area, to be compared with Fig. 2 of the reference paper. The 2D and 3D models give very similar results and agree with the figure in the paper.

Rc vs. I

- I In the Home toolbar, click Add Plot Group and choose ID Plot Group.
- 2 In the Settings window for ID Plot Group, type Rc vs. 1 in the Label text field.
- 3 Locate the Data section. From the Dataset list, choose Study I Rc vs. I/ Parametric Solutions I (sol2).
- 4 Locate the Plot Settings section.
- **5** Select the **y-axis label** check box. In the associated text field, type **Kelvin** contact resistance ([Omega]).
- 6 Locate the Axis section. Select the Manual axis limits check box.
- 7 In the x minimum text field, type 10.
- 8 In the x maximum text field, type 1e4.
- **9** In the **y minimum** text field, type **0.01**.
- 10 In the y maximum text field, type 10.
- II Select the x-axis log scale check box.
- 12 Select the y-axis log scale check box.

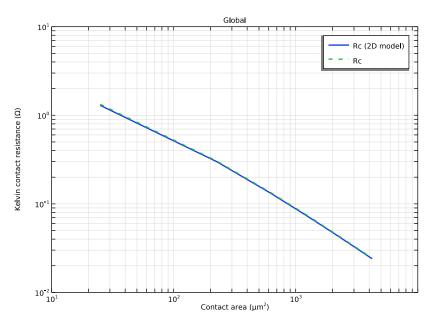
Global I

- I Right-click Rc vs. I and choose Global.
- 2 In the Settings window for Global, locate the y-Axis Data section.
- **3** In the table, enter the following settings:

Expression	Unit	Description	
-V2D_ode/I2D_1	Ω	Rc (2D model)	
semi.VO_2/semi.IO_1	Ω	Rc	

- 4 Locate the x-Axis Data section. From the Parameter list, choose Expression.
- 5 In the Expression text field, type 1^2.

- 6 From the Unit list, choose μm².
- 7 Select the **Description** check box. In the associated text field, type Contact area.
- **8** Click to expand the **Coloring and Style** section. Find the **Line style** subsection. From the **Line** list, choose **Cycle**.
- **9** From the **Width** list, choose **2**.
- 10 In the Rc vs. I toolbar, click Plot.



Repeat the steps to create a study to sweep the diffusion tap width w, while keeping the contact window size l at 5 um, to be compared with the result shown in Fig. 3 of the reference paper.

ADD STUDY

- I In the Home toolbar, click Add Study to open the Add Study window.
- 2 Go to the Add Study window.
- 3 Find the Studies subsection. In the Select Study tree, select General Studies>Stationary.
- 4 Click Add Study in the window toolbar.
- 5 In the Home toolbar, click Add Study to close the Add Study window.

STUDY 2 - RC VS. W

- I In the Model Builder window, click Study 2.
- 2 In the Settings window for Study, type Study 2 Rc vs. w in the Label text field.

Parametric Sweep

- I In the Study toolbar, click Parametric Sweep.
- 2 In the Settings window for Parametric Sweep, locate the Study Settings section.
- 3 Click + Add.
- **4** In the table, enter the following settings:

Parameter name	Parameter value list	Parameter unit
w (Diffusion tap width)	5.5 7 10 16 30 60	um

5 In the Study toolbar, click **Compute**.

Again evaluate and compare the bridge voltage and the terminal currents from the 3D semiconductor model and 2D simplified model. There is a good correlation between the results from the 2D and 3D models. Within each model, the input current agrees with the contact window current, and the bridge voltmeter current is essentially zero, both as expected.

RESULTS

Evaluation Group I - Rc vs. I

In the Model Builder window, under Results right-click Evaluation Group I - Rc vs. I and choose Duplicate.

Evaluation Group 2 - Rc vs. w

- I In the Model Builder window, under Results click Evaluation Group I Rc vs. I I.
- 2 In the **Settings** window for **Evaluation Group**, type Evaluation Group 2 Rc vs. w in the **Label** text field.
- 3 Locate the Data section. From the Dataset list, choose Study 2 Rc vs. w/ Parametric Solutions 2 (soll1).
- 4 In the Evaluation Group 2 Rc vs. w toolbar, click **= Evaluate**.

Duplicate the plot of the simulated Kelvin contact resistance R_c and make it a function of the diffusion tap width w, to be compared with Fig. 3 of the reference paper. The 2D and 3D models give very similar results and agree with the figure in the paper.

Rc vs. I

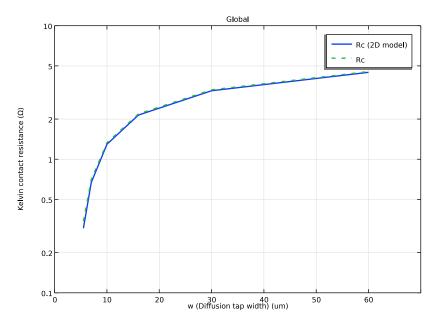
In the Model Builder window, right-click Rc vs. I and choose Duplicate.

Rc vs. w

- I In the Model Builder window, under Results click Rc vs. I I.
- 2 In the Settings window for ID Plot Group, type Rc vs. w in the Label text field.
- 3 Locate the Data section. From the Dataset list, choose Study 2 Rc vs. w/ Parametric Solutions 2 (soll1).
- 4 Locate the Axis section. In the x minimum text field, type 0.
- 5 In the x maximum text field, type 70.
- 6 In the y minimum text field, type 0.1.
- 7 Clear the x-axis log scale check box.

Global I

- I In the Model Builder window, expand the Rc vs. w node, then click Global I.
- 2 In the Settings window for Global, locate the x-Axis Data section.
- 3 From the Parameter list, choose Parameter value.
- 4 In the Rc vs. w toolbar, click **Plot**.



Create a 3D plot for the model thumbnail.

Electric Potential (semi)

In the Model Builder window, under Results right-click Electric Potential (semi) and choose Duplicate.

Model Thumbnail

- I In the Model Builder window, under Results click Electric Potential (semi) 2.
- 2 In the Settings window for 3D Plot Group, type Model Thumbnail in the Label text field.
- 3 Locate the Data section. From the Parameter value (I (um)) list, choose 5.
- 4 Locate the Plot Settings section. From the View list, choose New view.
- 5 Locate the Color Legend section. Clear the Show legends check box.
- 7 Locate the Plot Settings section. Click **Go to Source**.

Camera

- I In the Model Builder window, expand the View 3D 3 node, then click Camera.
- 2 In the Settings window for Camera, locate the Camera section.
- 3 From the View scale list, choose Manual.
- 4 In the z scale text field, type 5.
- 5 Click (Update.

Volume 1

- I In the Model Builder window, expand the Results>Model Thumbnail node, then click Volume 1.
- 2 In the Settings window for Volume, locate the Coloring and Style section.
- 3 Click Change Color Table.
- 4 In the Color Table dialog box, select Aurora>JupiterAuroraBorealis in the tree.
- 5 Click OK.

Transparency I

Right-click Volume I and choose Transparency.

Streamline I

- I In the Model Builder window, right-click Model Thumbnail and choose Streamline.
- 2 In the Settings window for Streamline, click Replace Expression in the upper-right corner of the Expression section. From the menu, choose Component I (compl)> Semiconductor>Currents and charge>semi.JX,...,semi.JZ Total current density, nodal value.

- 3 Locate the Streamline Positioning section. From the Positioning list, choose Starting-point controlled.
- 4 From the Entry method list, choose Coordinates.
- **6** In the **Y** text field, type -4.17 -2.5 -0.83 0.83 2.5 4.17 -4.17 -2.5 -0.83 0.83 2.5 4.17 -4.17 -2.5 -0.83 0.83
- **7** In the **Z** text field, type 0.083 0.083 0.083 0.083 0.083 0.083 0.25 0.25 0.25 0.25 0.25 0.417 0.417 0.417 0.417 0.417 0.417.
- 8 Locate the Coloring and Style section. Find the Point style subsection. From the Type list, choose Arrow.

Arrow Surface I

- I Right-click Model Thumbnail and choose Arrow Surface.
- 2 In the Settings window for Arrow Surface, click Replace Expression in the upper-right corner of the Expression section. From the menu, choose Component I (compl)> Semiconductor>Currents and charge>semi.JX,...,semi.JZ Total current density, nodal value
- 3 Locate the Arrow Positioning section. From the Placement list, choose Uniform anisotropic.
- 4 In the Number of arrows text field, type 18.
- 5 In the Z weight text field, type 10.
- 6 Locate the Coloring and Style section. From the Arrow base list, choose Head.
- 7 Select the Scale factor check box. In the associated text field, type 1e-6.

Selection I

- I Right-click Arrow Surface I and choose Selection.
- 2 In the Settings window for Selection, locate the Selection section.
- 3 Click Paste Selection.
- 4 In the Paste Selection dialog box, type 1 in the Selection text field.
- 5 Click OK.

Arrow Surface 2

- I In the Model Builder window, right-click Model Thumbnail and choose Arrow Surface.
- 2 In the Settings window for Arrow Surface, click Replace Expression in the upper-right corner of the Expression section. From the menu, choose Component I (compl)>

Semiconductor>Currents and charge>semi.JX,...,semi.JZ - Total current density, nodal value.

- 3 Locate the Arrow Positioning section. In the Number of arrows text field, type 30.
- 4 Locate the Coloring and Style section. From the Arrow length list, choose Logarithmic.
- **5** Select the **Scale factor** check box. In the associated text field, type 1.5e-6.

Selection I

- I Right-click Arrow Surface 2 and choose Selection.
- ${\bf 2}\;$ In the Settings window for Selection, locate the Selection section.
- 3 From the Selection list, choose Contact window.
- 4 In the Model Thumbnail toolbar, click Plot.

